November 2013



# SGL50N60RUFD 600 V, 50 A Short Circuit Rated IGBT

## **General Description**

Fairchild's RUFD series of Insulated Gate Bipolar Transistors (IGBTs) provide low conduction and switching losses as well as short circuit ruggedness. The RUFD series is designed for applications such as motor control, uninterrupted power supplies (UPS) and general inverters where short circuit ruggedness is a required feature.

## Features

- 50 A, 600 V, T<sub>C</sub> = 100°C
- Low Saturation Voltage:  $V_{CE}(sat) = 2.2 \text{ V} @ I_C = 50 \text{ A}$
- High Speed Switching
- High Input Impedance
- Short Circuit Rating

## **Applications**

Motor Control, UPS, General Inverter.

GCE



# Absolute Maximum Ratings T<sub>c</sub> = 25°C unless otherwise noted

Symbol	Description		Ratings	Unit
V <sub>CES</sub>	Collector-Emitter Voltage		600	V
V <sub>GES</sub>	Gate-Emitter Voltage		± 20	V
	Collector Current	@ T <sub>C</sub> = 25°C	80	А
I <sub>C</sub>	Collector Current	@ T <sub>C</sub> = 100°C	50	А
I <sub>CM (1)</sub>	Pulsed Collector Current		150	А
l <sub>F</sub>	Diode Continuous Forward Current	@ T <sub>C</sub> = 25°C	60	А
	Diode Continuous Forward Current	@ T <sub>C</sub> = 100°C	30	А
I <sub>FM</sub>	Diode Maximum Forward Current		90	А
T <sub>SC</sub>	Short Circuit Withstand Time	@ T <sub>C</sub> = 100°C	10	us
P <sub>D</sub>	Maximum Power Dissipation	@ T <sub>C</sub> = 25°C	250	W
	Maximum Power Dissipation	@ T <sub>C</sub> = 100°C	100	W
TJ	Operating Junction Temperature		-55 to +150	°C
T <sub>stg</sub>	Storage Temperature Range		-55 to +150	°C
TL	Maximum Lead Temp. for Soldering Purposes, 1/8" from Case for 5 Seconds		300	°C

Notes : (1) Repetitive rating : Pulse width limited by max. junction temperature

## **Thermal Characteristics**

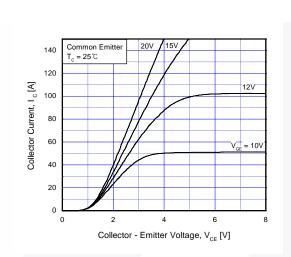
Symbol	Parameter	Тур.	Max.	Unit
R <sub>0JC</sub> (IGBT)	Thermal Resistance, Junction-to-Case		0.5	°C/W
$R_{\theta JC}(DIODE)$	Thermal Resistance, Junction-to-Case		1.0	°C/W
R <sub>0JA</sub> Thermal Resistance, Junction-to-Ambient			25	°C/W

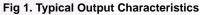
Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
Off Cha	racteristics					
BV <sub>CES</sub>	Collector-Emitter Breakdown Voltage	V <sub>GE</sub> = 0 V, I <sub>C</sub> = 250 uA	600			V
ΔB <sub>VCES</sub> / ΔT <sub>J</sub>	Temperature Coefficient of Breakdown Voltage	$V_{GE} = 0 V, I_C = 1 mA$		0.6		V/°C
I <sub>CES</sub>	Collector Cut-Off Current	$V_{CE} = V_{CES}, V_{GE} = 0 V$			250	uA
I <sub>GES</sub>	G-E Leakage Current	$V_{GE} = V_{GES}, V_{CE} = 0 V$			± 100	nA
On Chai	acteristics					
V <sub>GE(th)</sub>	G-E Threshold Voltage	$Ic = 50 \text{ mA}, V_{CE} = V_{GE}$	5.0	6.0	8.5	V
	Collector to Emitter	$I_{\rm C} = 50 \text{ A},  V_{\rm GE} = 15 \text{ V}$		2.2	2.8	V
V <sub>CE(sat)</sub>	Saturation Voltage	I <sub>C</sub> = 80 A, V <sub>GE</sub> = 15 V		2.5		V
	c Characteristics					
C <sub>ies</sub>	Input Capacitance	V <sub>CE</sub> =30 V, V <sub>GE</sub> = 0 V,		3311		pF
C <sub>oes</sub>	Output Capacitance	$v_{CE}=30 v_{,} v_{GE}=0 v_{,}$ f = 1 MHz		399		pF
C <sub>res</sub>	Reverse Transfer Capacitance			139		pF
t <sub>d(on)</sub>	ng Characteristics Turn-On Delay Time Rise Time	-		26 89		ns ns
t <sub>d(on)</sub>		4		-		ns
t <sub>r</sub>	Turn-Off Delay Time	$V_{CC} = 300 \text{ V}, \text{ I}_{C} = 50 \text{ A},$ $R_{G} = 5.9 \Omega, V_{GE} = 15 \text{ V},$		66	100	ns
t <sub>d(off)</sub> t <sub>f</sub>	Fall Time			118	200	ns
ч E <sub>on</sub>	Turn-On Switching Loss	Inductive Load, $T_c = 25^{\circ}C$		1.68		mJ
∟ <sub>on</sub> E <sub>off</sub>	Turn-Off Switching Loss			1.03		mJ
E <sub>ts</sub>	Total Switching Loss	-		2.71	3.8	mJ
t <sub>d(on)</sub>	Turn-On Delay Time			28		ns
t <sub>r</sub>	Rise Time	-		91		ns
t <sub>d(off)</sub>	Turn-Off Delay Time	V <sub>CC</sub> = 300 V, I <sub>C</sub> = 50 A,		68	110	ns
t <sub>f</sub>	Fall Time	$R_{G} = 5.9 \Omega, V_{GE} = 15 V,$		261	400	ns
E <sub>on</sub>	Turn-On Switching Loss	Inductive Load, $T_C = 125^{\circ}C$		1.7		mJ
E <sub>off</sub>	Turn-Off Switching Loss	Ĭ		2.31		mJ
E <sub>ts</sub>	Total Switching Loss			4.01	5.62	mJ
T <sub>sc</sub>	Short Circuit Withstand Time	V <sub>CC</sub> = 300 V, V <sub>GE</sub> = 15 V @ T <sub>C</sub> = 100°C	10			us
Q <sub>q</sub>	Total Gate Charge	Ŭ		145	210	nC
Q <sub>ge</sub>	Gate-Emitter Charge	$V_{CE} = 300 \text{ V}, I_C = 50 \text{ A},$		25	35	nC
Q <sub>gc</sub>	Gate-Collector Charge	V <sub>GE</sub> = 15 V		70	100	nC
L <sub>e</sub>	Internal Emitter Inductance	Measured 5mm from PKG		18		nH

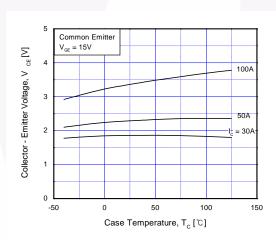
# Electrical Characteristics of DIODE $T_{C} = 25^{\circ}C$ unless otherwise noted

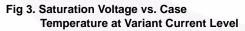
Symbol	Parameter Test Conditions		tions	Min.	Тур.	Max.	Unit
V <sub>FM</sub> I	Diode Forward Voltage	$I_{\rm F} = 30 \text{ A} \qquad \qquad \frac{T_{\rm C} = 25^{\circ}\text{C}}{T_{\rm C} = 100^{\circ}\text{C}}$	$T_{C} = 25^{\circ}C$		1.9	2.8	V
				1.8		v	
t <sub>rr</sub> Diode Reverse Recovery Time		$T_{C} = 25^{\circ}C$		70	100	2	
t <sub>rr</sub>	Didde Reverse Recovery Time	$T_{\rm C} = 1$	$T_{\rm C} = 100^{\circ}{\rm C}$		140		ns
1	Irr Diode Peak Reverse Recovery Current	I <sub>F</sub> = 30 A,	$T_{C} = 25^{\circ}C$		6	7.8	~
rr		di <sub>F</sub> /dt=200 A/us	$T_{\rm C} = 100^{\circ}{\rm C}$		8		A
Q <sub>rr</sub>	Diode Reverse Recovery Charge		$T_{\rm C} = 25^{\circ}{\rm C}$		200	360	nC
			$T_C = 100^{\circ}C$		580		nc

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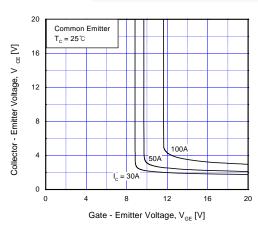


Fig 5. Saturation Voltage vs.  $\rm V_{GE}$ 

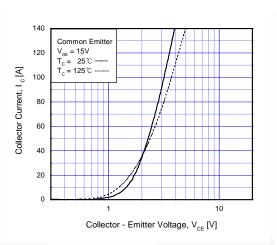
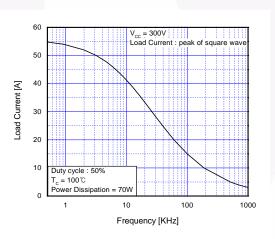
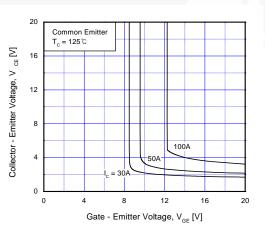


Fig 2. Typical Saturation Voltage Characteristics



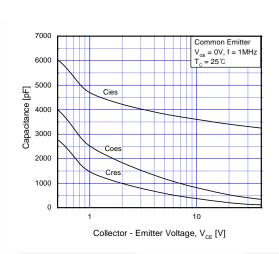


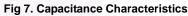


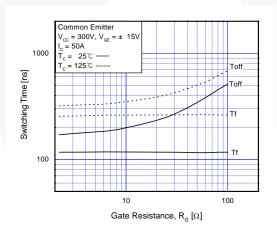


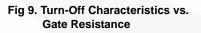
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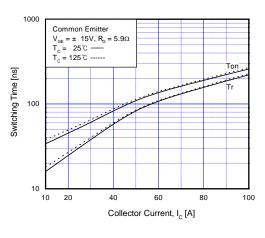
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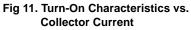


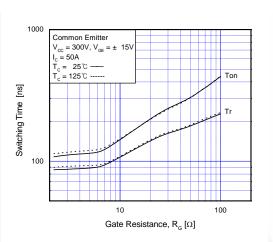














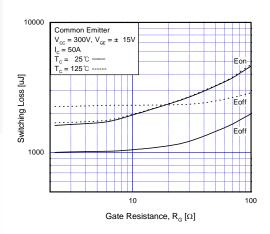
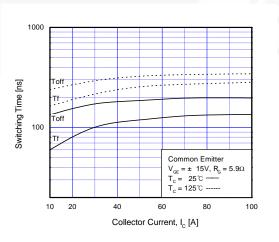
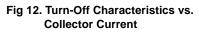
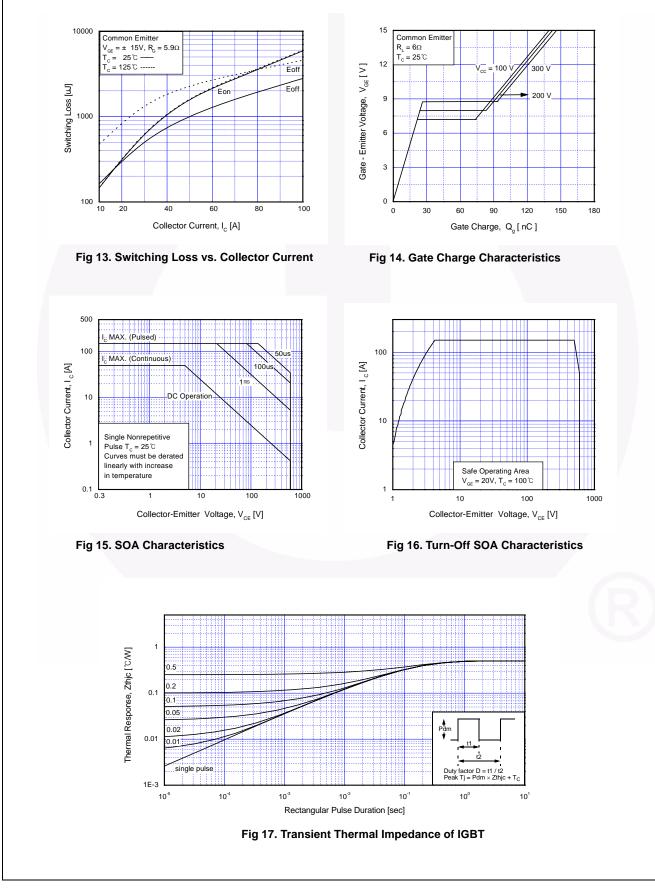


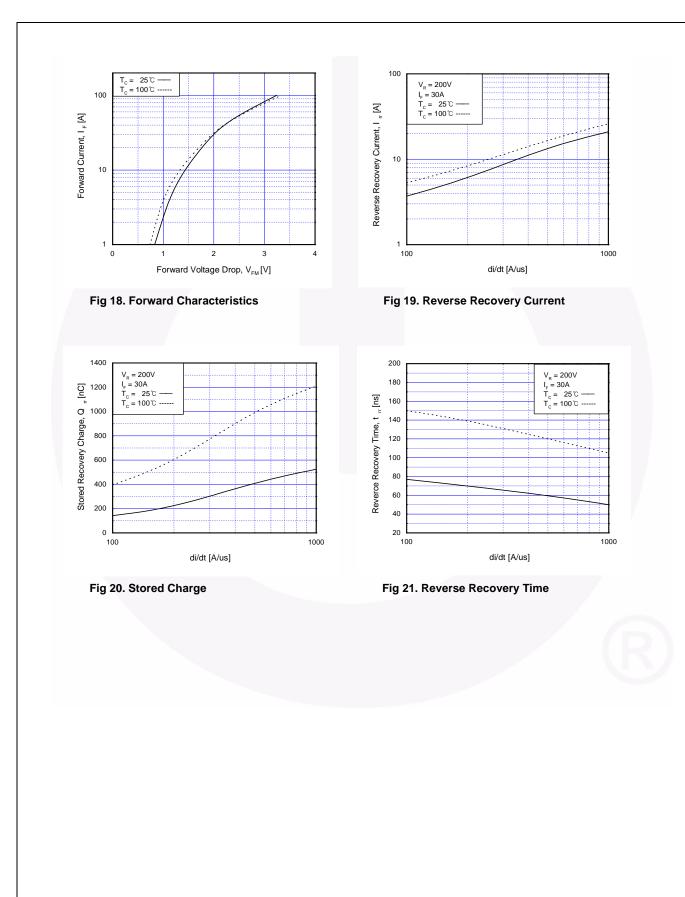
Fig 10. Switching Loss vs. Gate Resistance

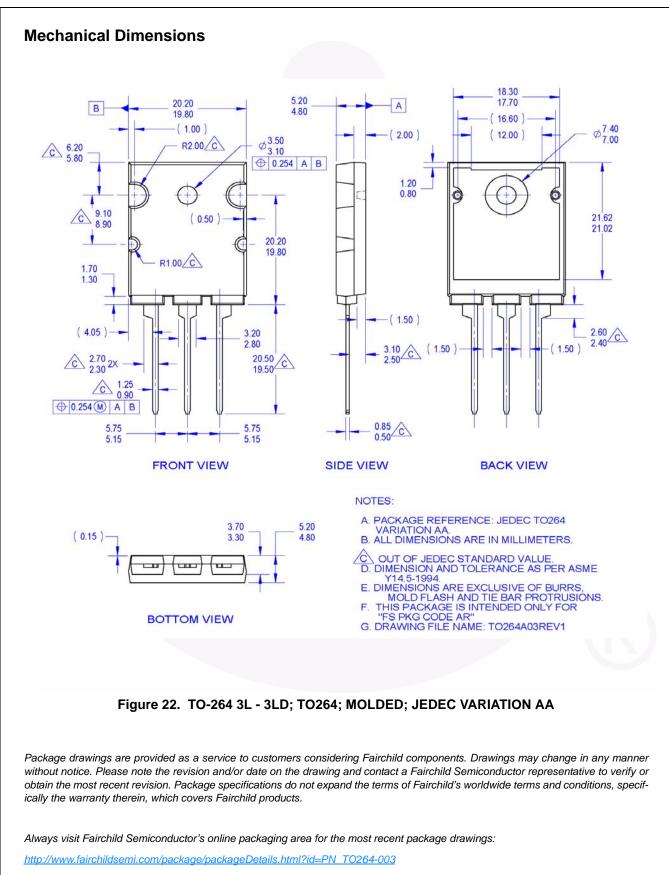




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